

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/696,623	YEN, WEI	
Examiner	Art Unit	
Hieu c. Le	2142	

SEARCHED					
Class	Subclass	Date	Examiner		
709	203	12/23/2005	HL ✓		
	217-219				
715	501.1				
705	1,26				
	27				
707	9-10				
	102	A	<b>V</b>		
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IN	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
709	217-219	512.05	HU			
715	501.1	<u> </u>	Y			
705	1,16-27					
707	9-10					

SEARCH (INCLUDING SEAI		, )
	DATE	EXMR
Consulted with P.E	5/2/2005	HĽ
EL Nabil Hady class 709	5/12/2005	HL
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